

HITACHI
Inspire the Next¹

FT230

Simply Smarter



COATINGS

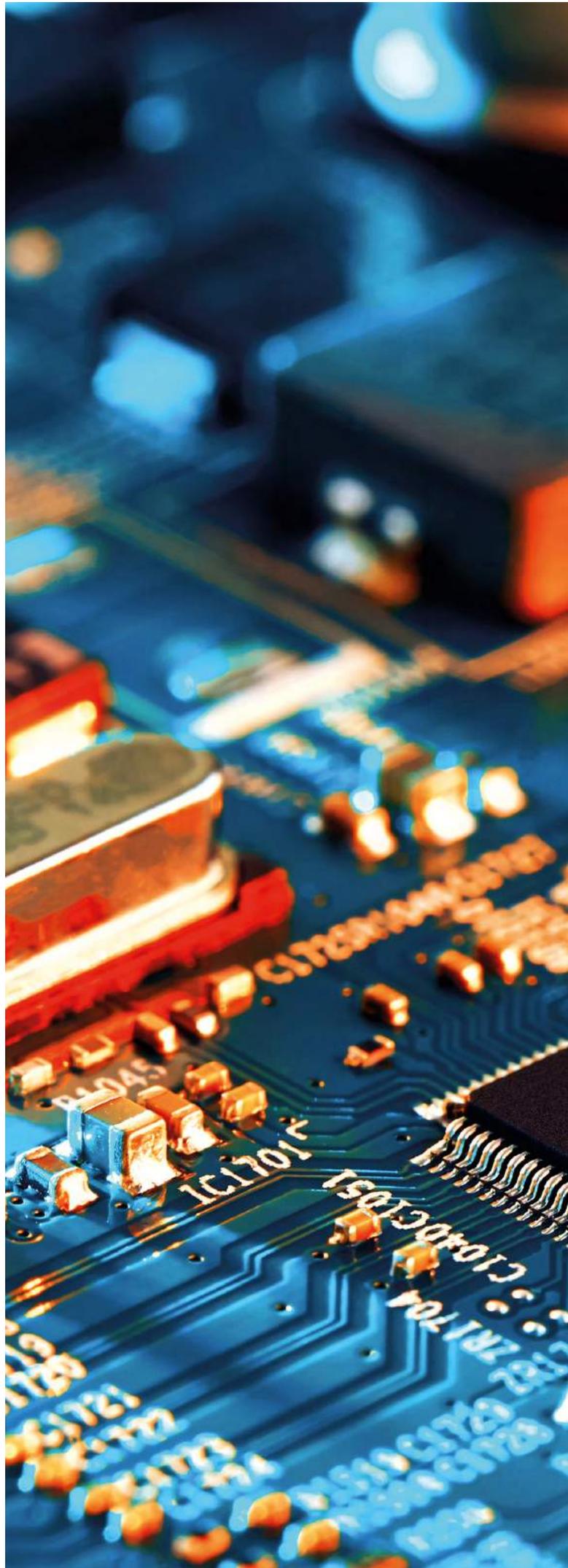
Quality control that keeps pace with production

XRF analysis has always been fast. But if you've been taking XRF measurements within a production environment, you'll know most of the time spent with your XRF equipment is in the preparation and set up, not the actual analysis. And with increasingly tiny and complex components, tightening specifications and the need for 100% inspection, every second matters.

The new FT230 from Hitachi cuts right to the heart of this problem. Every element of the FT230 is designed to reduce the time it takes to complete an XRF measurement so that you can act on your results faster, reducing waste and increasing throughput. At a fundamental level, we've made it easier and simpler to interact with the instrument.

All you need to do is load your part and run the Find My Part™ routine and the FT230 will find the features that need to be measured, choose the correct analysis program and send the results where you need them. Operators have fewer decisions to make and can spend more time performing other tasks.

There's no need for your XRF to be the bottleneck in your production. From minute electronics components to large-scale plated parts, the FT230 helps you get more done in less time, making it easier to achieve 100% inspection.



Break Free with the FT230



FAST THROUGHPUT

Automated focusing speeds up sample loading time, even when switching between components of different shapes and sizes.



RAPID SETUP

The smart recognition feature Find My Part™ automatically selects the right analysis routine and locates the correct spot for analysis.



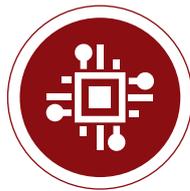
EXCELLENT VISIBILITY

The analyzer includes an option for a wide-view camera and presents the sample view over a large area of the screen. This, plus adjustable LED lighting, makes it easy to pinpoint the area of interest.



MAXIMUM UPTIME

Self-checking diagnostics confirm the stability and health of the analyzer. This data can be shared with Hitachi's support team for expert monitoring using Hitachi's secure ExTOPE Connect cloud data service.



SEAMLESS INTEGRATION

Integrates seamlessly with other software systems, such as QMS, SCADA, MES and ERP, with easy, customizable data export and report creation for internal users and external customers.



EASY TO USE

The new user interface has been designed for users who are not XRF experts. Intuitive and uncluttered, the right analysis is only a click away.



POWERFUL VERSATILITY

The FT230 simplifies your testing program with the capability to analyze up to four coating layers plus the substrate, as well as bulk materials including metal alloys and plating baths.



Smart recognition

The FT230 includes newly developed smart part recognition for fast and foolproof analysis setup. This automates the most frustrating and potentially error-prone part of the analysis setup - selecting the right recipe for each analysis location.

Find My Part™ selects the right analytical routine for the part you are measuring. Let the XRF make decisions about where and how to measure, and send the results and reports where you need them. This is faster than a manual process, reduces the potential for user error and frees up operators to perform other tasks.

When you come to analyzing new parts, it's simple to add them to the on-board library.

Automated focusing

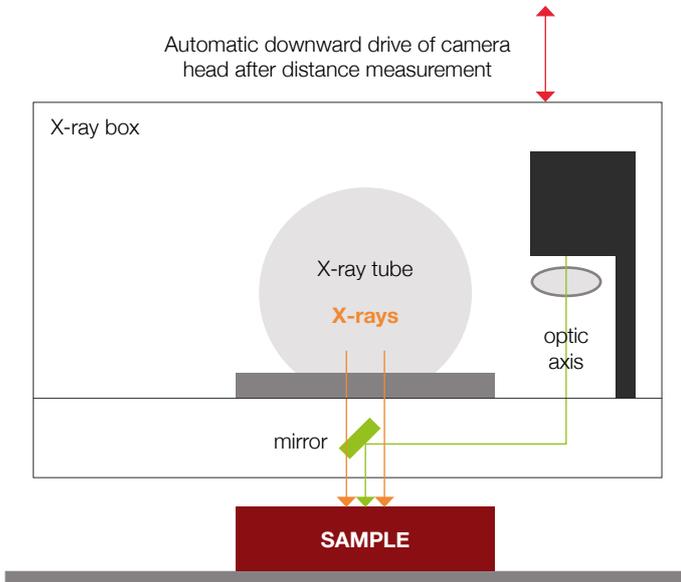
For maximum accuracy and precision for your XRF analysis, it is essential to maintain a known distance between the tube, the part being measured and the detector. Even small variations in the focal length can have an impact on the reliability of the results, giving you thickness measurements that are either too thick or too thin, depending on whether the X-ray tube is too near or too far from the sample.

We have improved instrument setup by providing the user with a choice of two automated focusing options: **auto approach** and **auto focus**.

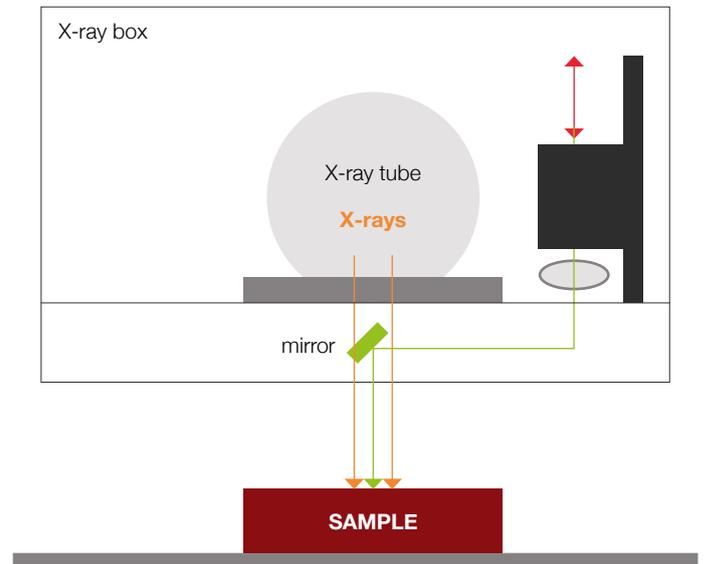
Auto approach is used when a fixed working distance is preferred. With a single click, the instrument automatically moves the X-ray tube to that distance. **Auto focus**, sometimes called distance independent measurement, allows the instrument to get accurate results even when the working distance changes.

This can save a huge amount of time over a day of analysis, especially when measuring components that have complex geometries or different samples with features of varying heights.

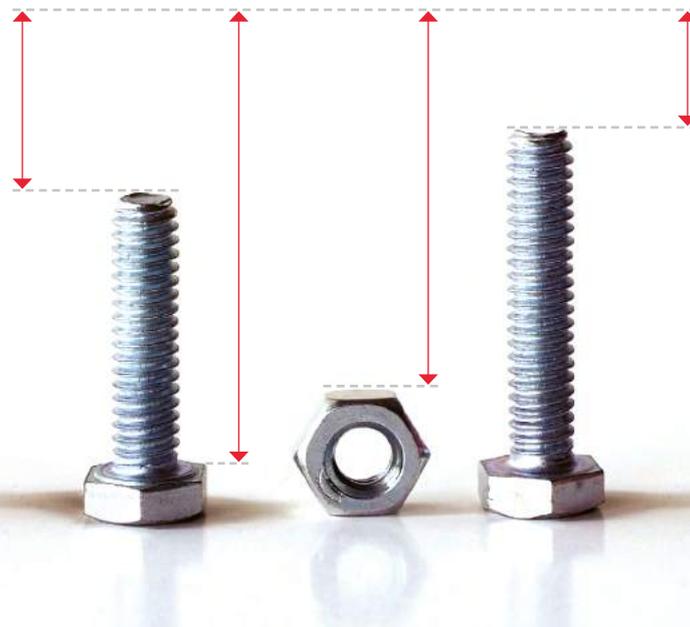
AUTO APPROACH FUNCTION



AUTO FOCUS FUNCTION



MEASURE PARTS WITH DIFFERENT HEIGHTS



Smart and simple interface

The FT230 is the first product to run Hitachi's new FT Connect software, building on over four decades of experience and user feedback on established software including SmartLink and X-ray Station.

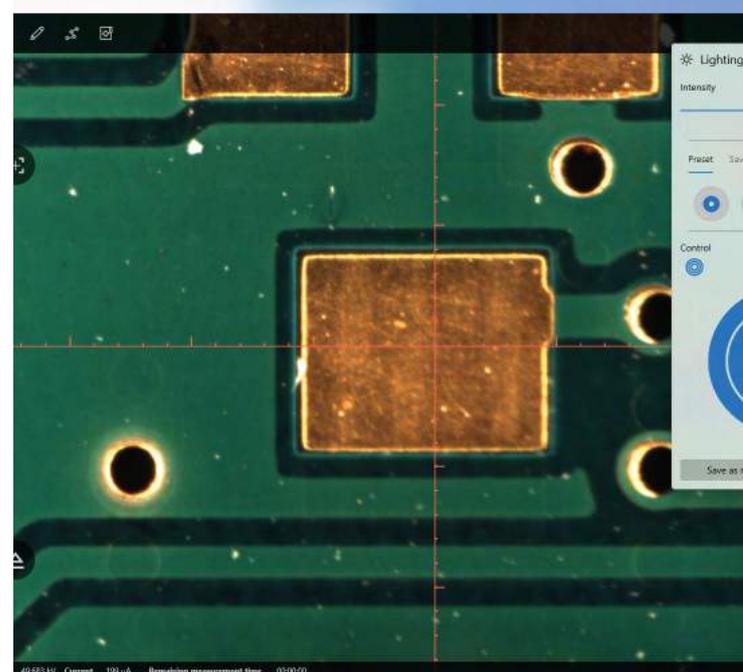
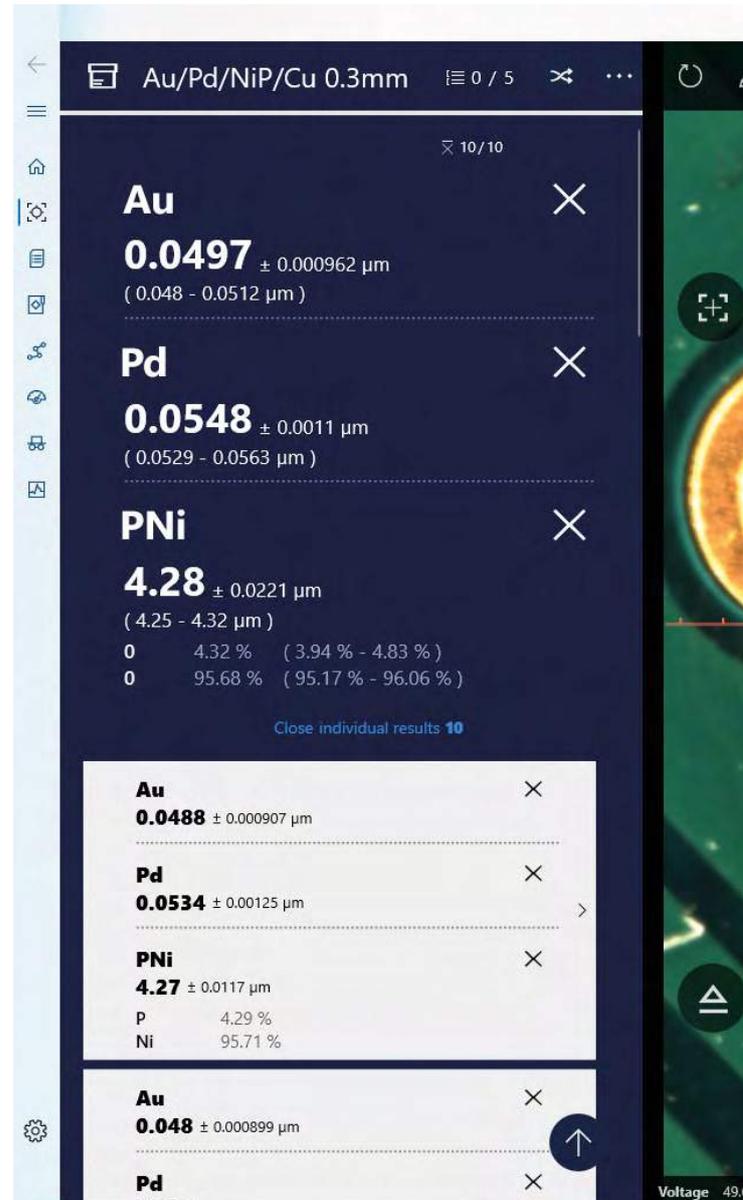
FT Connect gets you results faster. The most notable difference is the interface. Instead of a screen full of controls and options that the user needs to navigate, the FT Connect screen prioritizes the sample view and clear presentation of the analysis results. This makes it much easier to position parts correctly and act quickly on the results.

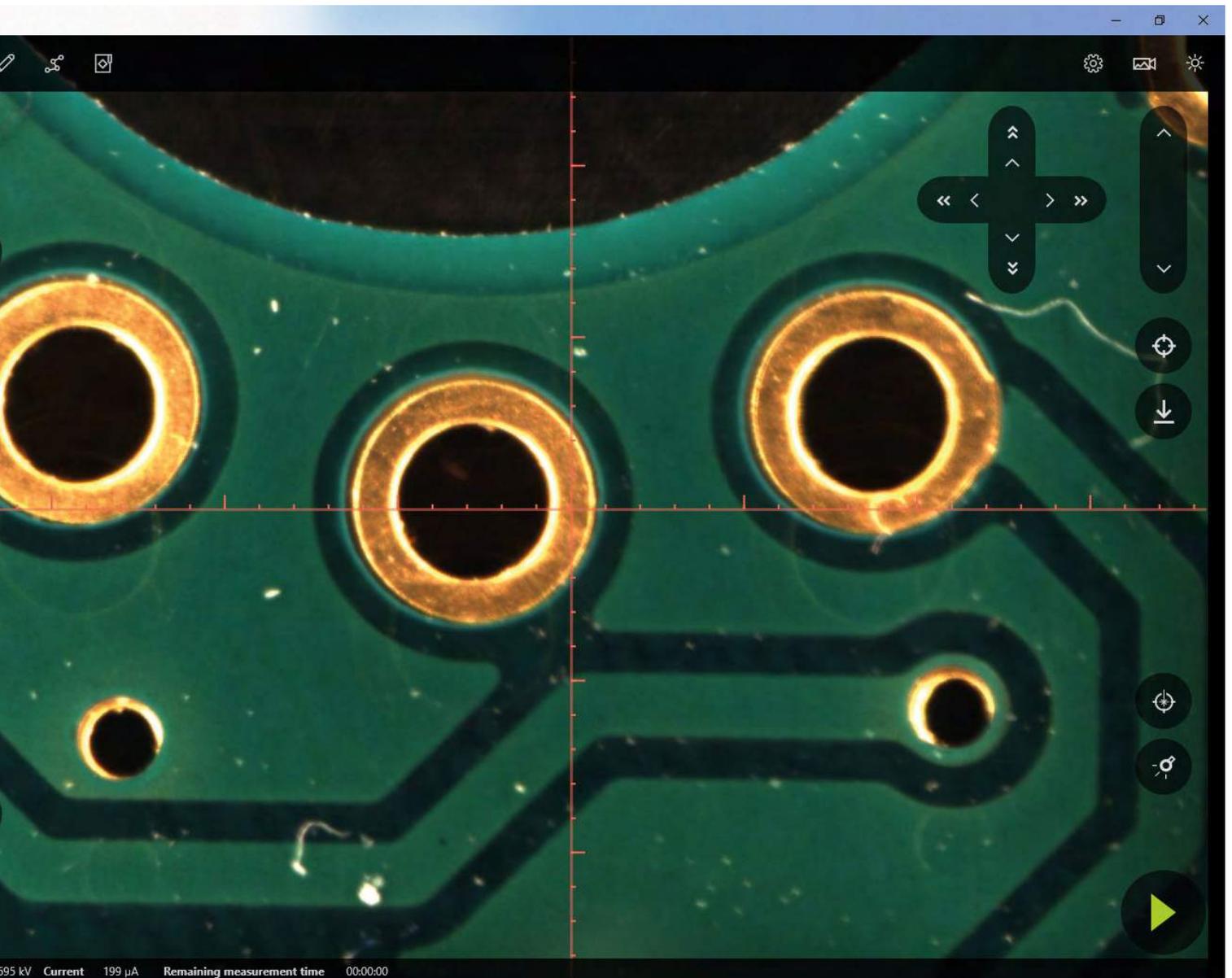
The routine measurement screen – where users spend nearly all their time with the XRF – shows only the controls needed to set up and start a measurement and evaluate results. Users can easily create calibrations, set up report templates and data handling rules as well as develop more complex analysis programs, patterns and parts using the guided selection tools, all just a few clicks away. FT Connect gives you the simplicity to run routine analysis and interpret results fast, while still incorporating the powerful analytical options for more advanced situations, including root cause analysis.

LARGE SAMPLE VIEW

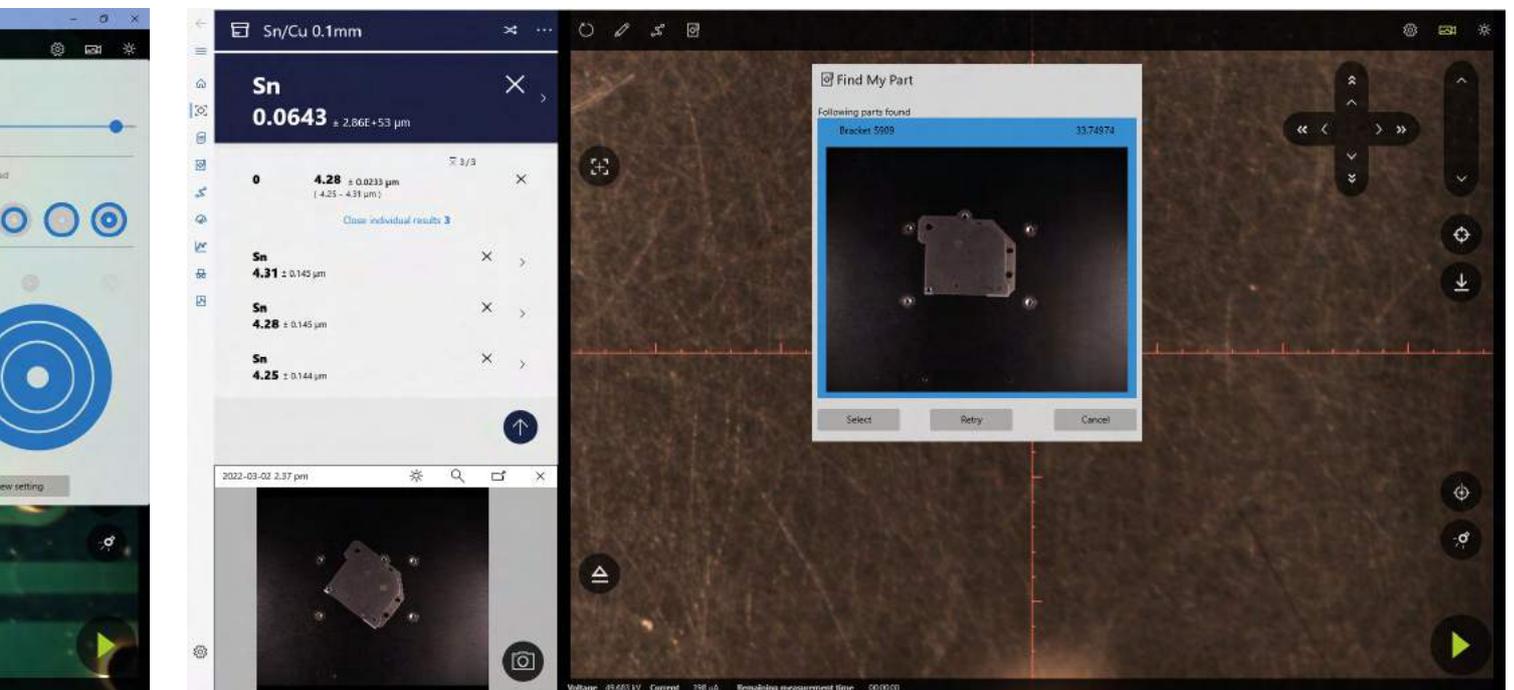
One of the most frustrating aspects of setting up a sample for analysis is simply finding the right area on the PCB or metal component. In addition to the smart recognition features, the FT230 presents the largest in-software sample view in the industry. With the majority of the screen showing the part, operators can more easily view the features on the surface, helping them pinpoint the right area for analysis and making it much easier to navigate around the surface of the part.

In addition, the FT230 comes with the option of a second, wide-view camera, to make it even easier and faster to find features on a large circuit board or metal plated component. When the two cameras are used together, you can quickly switch between measurement sites on a single part or between multiple parts in the chamber, without getting 'lost' in the details.





595 kV Current 199 μ A Remaining measurement time 00:00:00



Sn/Cu 0.1mm

Sn
0.0643 $\pm 2.86E+53 \mu\text{m}$

0 4.28 $\pm 0.0233 \mu\text{m}$
(4.23 - 4.31 μm)

Close individual results 3

Sn 4.31 $\pm 0.142 \mu\text{m}$

Sn 4.28 $\pm 0.145 \mu\text{m}$

Sn 4.25 $\pm 0.144 \mu\text{m}$

2022-03-02 2:37 pm

Voltage: 49.683 kV Current 756 μ A Remaining measurement time 00:00:00

FT230 technical specifications

| Analysis | Details |
|--------------------------|---|
| X-ray tube | Tungsten (W) target microfocus X-ray tube, top-down orientation Maximum 50 kV, 1000 μ A, 50 W |
| Detector | High resolution, large area 50 mm ² SDD |
| Primary filters | 5 primary filters (2x Al, Ti, Mo, Ni) + 1 open position |
| Collimators | 4 collimators available in rectangular and round sizes from 0.01 x 0.25 mm to 1 mm (0.5 x 10 mil to 40 mil) |
| Element range | Al (13) - U (92) |
| Number of layers | Maximum 5 (4 layers plus substrate) |
| Selectable elements | Free selection |
| Atmospheric compensation | Automatic temperature and pressure compensation |
| Atmosphere | Air |
| Norms | Measurement of coatings by energy dispersive X-ray fluorescence ASTM B568, DIN ISO 3497 |

| Sample positioning | Details |
|---|---|
| Largest sample size | 500 x 400 x 150 mm (19.7 x 15.7 x 5.9") |
| Stage travel | 250 x 200 mm (9.8 x 7.8") |
| Stage size | 900 x 600 mm (35.4 x 23.6") - motorized stage, slotted chamber 270 x 210 mm (10.6 x 8.2") - motorized stage, closed chamber 540 x 540 mm (21.2 x 21.2") - fixed stage |
| Stage speed (motorized configuration) | 80 mm/s (3.1"/s) |
| Stage precision (motorized configuration) | $\leq 5 \mu\text{m}$ (0.002") |
| Maximum sample weight | 10 kg (22 lb) - fixed stage 5 kg (11 lb) - motorized stage |
| Z-axis travel | 205 mm (8") |
| Working distance | 5 mm (0.2") - nominal, focus laser 5 to 67 mm (0.2 to 2.6") - auto focus/auto approach (option) |
| Stage, Z-axis control | Software controls and 3-axis joystick with start button (optional) |
| Focusing | Laser focus (Class 1 laser product), distance independent measurement / auto focus (option), automatic working distance approach (option) |
| Field of view (camera) | 7.1 x 5.3 mm (0.28 x 0.2") |
| Field of view (wide-view camera, option) | 250 x 200mm (9.8 x 7.8") |
| Positioning assistance | Positioning laser, pre-positioning laser (motorized stage configuration) |

| Software | Details |
|-------------------|--|
| User interface | FT Connect |
| Standard features | Coatings analysis (FP and empirical), bulk materials analysis (FP and empirical), multi-point programming, qualitative mode, data history, diagnostics, ExTOPE Connect Password protected, multiple access levels controlled software |
| Smart recognition | Find My Part™ (machine vision, QR/barcode scan, text lookup) |
| Languages | Chinese Simplified, Chinese Traditional, Czech, English, French, German, Italian, Japanese, Korean, Portuguese, Russian, Spanish |
| PC specification | Windows 10 64-bit PC |

Our experts are happy to speak with you about specific technical details related to your application.



| Dimensions and working environment | Details |
|---|--|
| Dimensions and working environment | |
| Dimensions | 600 x 815 x 745 mm (23.6 x 32.1 x 29.3") - closed chamber 900 x 931 x 745 mm (35.4 x 36.7 x 29.3") - slotted chamber, motorized stage |
| Weight (excluding PC) | 140 kg (308 lb) |
| Temperature range | 10 - 40 oC (50 - 104 oF) |
| Humidity range | Max 90% relative humidity (non-condensing) |
| Power requirements | 100 - 240 V +/- 10%; 47 - 63 Hz; 1.5 A |
| Signal tower (option) | 3-tier red/yellow/green indicator (X-rays on/shutter open/instrument powered on) |

| Warranty | Details |
|-------------------|---|
| Standard duration | 1 year |
| Available options | Extended factory warranty and service contracts |

| Typical performance for Au/NiP/Cu | Au | NiP |
|---|--|---|
| Tested range | 0.051 - 0.09 μm (2.00 - 3.55 μin) | 2.7 - 5.7 μm (106 - 225 μin) |
| Standard error | 0.025 μm (1 μin) or 5% relative, whichever is greater | 0.025 μm (1 μin) or 5% relative, whichever is greater |
| Precision (2 σ) at 30s, 0.3 mm collimator | 0.0025 μm @ 0.09 μm (0.099 μin @ 3.55 μin) | 0.026 μm @ 5.7 μm , 8 %P (1.02 μin @ 225 μin , 8 %P) |

| Typical performance for Sn/Ni/Cu | Sn | Ni |
|---|--|--|
| Tested range | 2.16 - 9.2 μm (85 - 362 μin) | 0.97 - 15.1 μm (38 - 595 μin) |
| Standard error | 0.025 μm (1 μin) or 5% relative, whichever is greater | 0.025 μm (1 μin) or 5% relative, whichever is greater |
| Precision (2 σ) at 30s, 0.3 mm collimator | 0.014 μm @ 4.9 μm (0.55 μin @ 193 μin) | 0.036 μm @ 4.7 μm (1.42 μin @ 185 μin) |

Data handling for Industry 4.0

FT Connect is built for data. Send results and reports where and when you need them with the FT230's flexible data handling features.

CONNECTIVITY

For instant feedback and floor-level decision making, the results are prominently displayed on the main measurement screen, enabling users to take appropriate action immediately. In addition, the FT230 can send results in JSON format, ready for integration with your SCADA, QMS, MES, and ERP systems, integrating seamlessly with wider production processes you already have in place.

Diagnostics and instrument health information can be shared with Hitachi's technical support team over ExTOPE Connect – Hitachi's cloud-based data management and storage service – to help keep your FT230 operating with maximum reliability and efficiency.

REPORTING

The FT Connect software includes powerful reporting features that allow you to generate customizable reports for internal or external customers. Data can also be exported in JSON or spreadsheet format to local or networked drives for close inspection by your analytical experts.



Our Service

Hitachi High-Tech's global network of service hubs offers a full range of technical support to keep you up and running:



GLOBAL HELP DESKS

Whenever you have a problem, we're ready to help.



ONLINE DIAGNOSTICS

In-depth and rapid support via our website.



TRAINING

To help you get the most out of your analyzer and its full range of features.



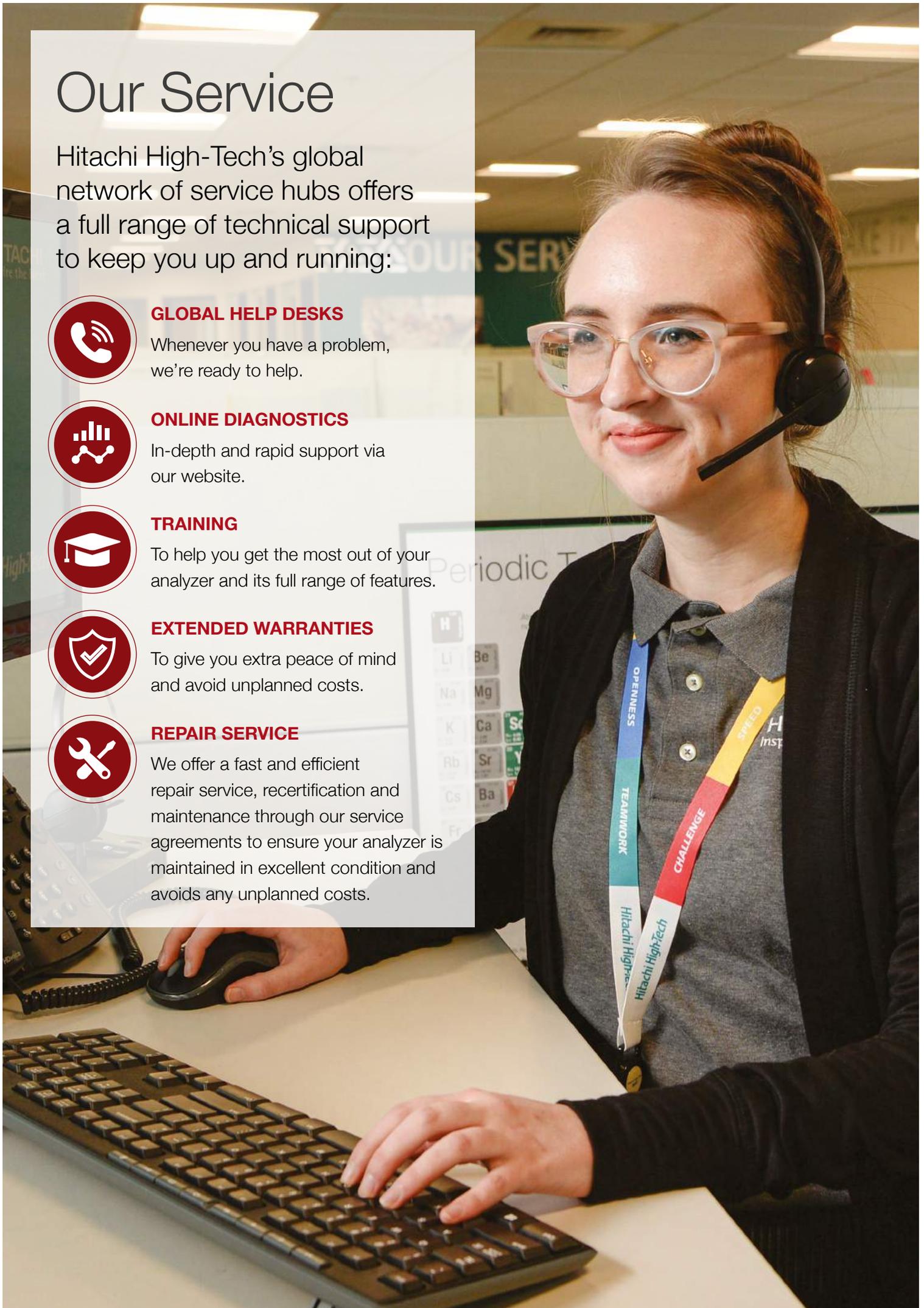
EXTENDED WARRANTIES

To give you extra peace of mind and avoid unplanned costs.



REPAIR SERVICE

We offer a fast and efficient repair service, recertification and maintenance through our service agreements to ensure your analyzer is maintained in excellent condition and avoids any unplanned costs.



What next?

Contact one of our experts today at contact@hitachi-hightech.com to discuss how the FT230 can help speed up your quality control testing and achieve 100% inspection.

MORE INFORMATION

To find out more about the FT230, visit hhtas.net/FT230



Other products

We have been providing coatings and bulk material analysis instruments to a wide range of industries for over 45 years.

- **RoHS screening:** dedicated solutions for RoHS contaminants including phthalates.
- **Handheld XRF:** for rapid and powerful elemental analysis for a wide range of applications.
- **Electromagnetic Gauges:** for rapid thickness measurement of PCB copper, paint, anodizing, electroplating and galvanizing.
- **Thermal Analysis:** DSC, STA, DMA and TMA for advanced materials and physical properties analysis.
- **Atomic Absorption:** for plating bath analysis of major and minor elements as well as contaminants.

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